

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
YOUNG, ALAN

Examiner

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Art Unit

3689

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,393,415	05-2002	Getchius et al.	707/2
*	B	US-2004/0199445	10-2004	Eder, Jeff Scott	705/035
*	C	US-6,539,392	03-2003	Rebane, George J.	707/101
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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